

STB200NF03-VB Datasheet N-Channel 30-V (D-S) MOSFET

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N-Channel MOSFET

GO

PRODUCT SUMMARY					
V _{DS} (V)	R _{DS(on)} (Ω)	I _D (A)	Q _g (Typ)		
30	0.0023 at V _{GS} = 10 V	150	82 nC		
	0.0032 at V _{GS} = 4.5 V	120	02 HC		



FEATURES

- Trench Power MOSFET
- 100 % R_g and UIS Tested
- Compliant to RoHS Directive 2011/65/EU

APPLICATIONS

- OR-ing
- Server •
- DC/DC •

Parameter		Symbol	Limit	Unit
Drain-Source Voltage	V _{DS}	30	V	
Gate-Source Voltage		V _{GS}	± 20	V
	T _C = 25 °C		150	
Continuous Drain Current (T _J = 175 °C)	T _C = 70 °C		120	
	T _A = 25 °C	I _D	35.8 ^{b, c}	A
	T _A = 70 °C		27 ^{b, c}	~
Pulsed Drain Current		I _{DM}	500	
Avalanche Current Pulse		I _{AS}	39	
Single Pulse Avalanche Energy	he Energy L = 0.1 mH		94.8	mJ
Continuous Source-Drain Diode Current	T _C = 25 °C	1-	90 ^{a, e}	^
Continuous Source-Drain Diode Current	T _A = 25 °C	I _S	3.13 ^{b, c}	— A
	T _C = 25 °C		250 ^a	
Maximum Power Dissipation	T _C = 70 °C	Р	175	10/
	T _A = 25 °C	P _D	3.75 ^{b, c}	W
	T _A = 70 °C		2.63 ^{b, c}	
Operating Junction and Storage Temperature Ra	T _J , T _{stq}	- 55 to 175	°C	

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Тур.	Max.	Unit	
Maximum Junction-to-Ambient ^{b, d}	$t \le 10 \text{ sec}$	R _{thJA}	32	40	°C/W	
Maximum Junction-to-Case	Steady State	R _{thJC}	0.5	0.6	0/10	

Notes:

a. Based on $T_C = 25$ °C. b. Surface mounted on 1" x 1" FR4 board. c. t = 10 sec.

d. Maximum under steady state conditions is 90 °C/W.

Parameter	Symbol	rwise noted) Test Conditions	Min	Turn	Max	Unit	
Static	Symbol	lest Conditions	Min.	Тур.	Max.	Unit	
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} = 0 V, I _D = 250 μA	30		-	V	
V _{DS} Temperature Coefficient	ΔV _{DS} /T _J	V _{GS} = 0 V, I _D = 250 μA		35			
		I _D = 250 μA				mV/°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	V _{DS} = V _{GS} , I _D = 250 µA	4.5	- 7.5	0.5		
Gate-Source Threshold Voltage	V _{GS(th)}		1.5		2.5	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 V, V_{GS} = \pm 20 V$			± 100	nA	
Zero Gate Voltage Drain Current	I _{DSS}	$V_{DS} = 30 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$			1	μA	
		$V_{DS} = 30 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ T}_{J} = 55 \text{ °C}$			10		
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	90			A	
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = 10 V, I _D = 38.8 A		0.0023		Ω	
		$V_{GS} = 4.5 \text{ V}, \text{ I}_{D} = 37 \text{ A}$		0.0032			
Forward Transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 38.8 A		160		S	
Dynamic ^b				-		-	
Input Capacitance	C _{iss}			6201		pF	
Output Capacitance	C _{oss}	V_{DS} = 15 V, V_{GS} = 0 V, f = 1 MHz		1725			
Reverse Transfer Capacitance	C _{rss}			970			
Total Gate Charge	Qg	V_{DS} = 15 V, V_{GS} = 10 V, I_{D} = 38.8 A		171	257	nC	
Total Gate Gharge	_	V _{DS} = 15 V, V _{GS} = 4.5 V, I _D = 28.8 A		81.5	123		
Gate-Source Charge	Q _{gs}			34			
Gate-Drain Charge	Q _{gd}			29			
Gate Resistance	R _g	f = 1 MHz		1.4	2.1	Ω	
Turn-On Delay Time	t _{d(on)}			18	27	- ns	
Rise Time	t _r	V_{DD} = 15 V, R_L = 0.625 Ω		11	17		
Turn-Off Delay Time	t _{d(off)}	$\text{I}_\text{D}{\cong}24$ A, V_GEN = 10 V, R_g = 1 Ω		70	105		
Fall Time	t _f			10	15		
Turn-On Delay Time	t _{d(on)}			55	83		
Rise Time	t _r	$V_{DD} = 15 \text{ V}, \text{ R}_{\text{I}} = 0.67 \Omega$		180	270		
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 22.5 \text{ A}, \text{ V}_{\text{GEN}} = 4.5 \text{ V}, \text{ R}_{\text{g}} = 1 \Omega$		55	83		
Fall Time	t _f			12	18		
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	۱ _S	T _C = 25 °C			120		
Pulse Diode Forward Current ^a	I _{SM}				120	A	
Body Diode Voltage	V _{SD}	I _S = 22 A		0.8	1.2	V	
Body Diode Reverse Recovery Time	t _{rr}	-		52	78	ns	
Body Diode Reverse Recovery Charge	Q _{rr}			70.2	105	nC	
Reverse Recovery Fall Time	ta	$I_F = 20 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^\circ\text{C}$		27		- ns	
Reverse Recovery Rise Time	t _b			25			

Notes:

a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle ≤ 2 %.

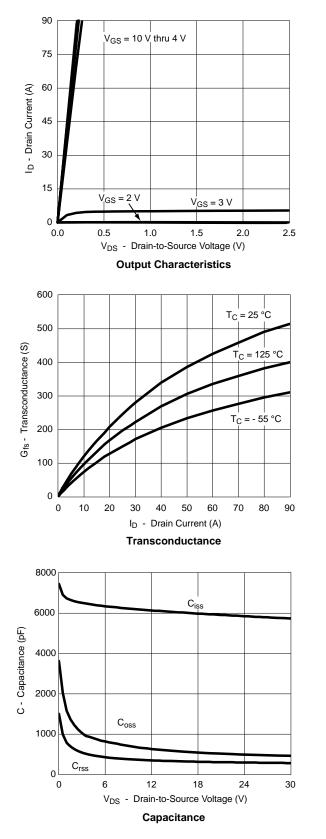
b. Guaranteed by design, not subject to production testing.

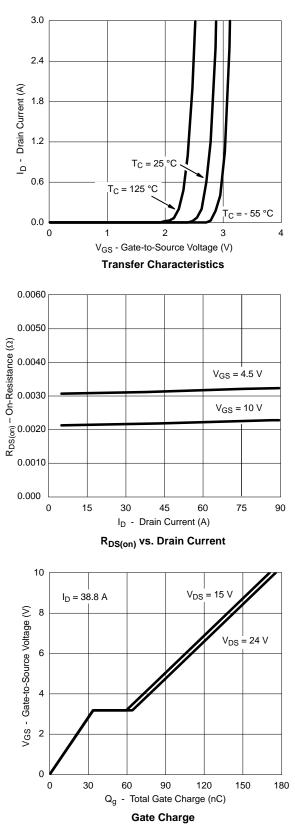
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

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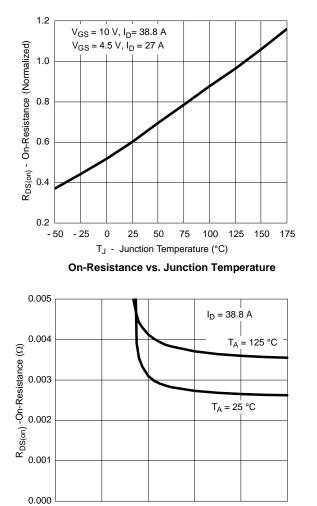


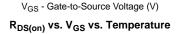


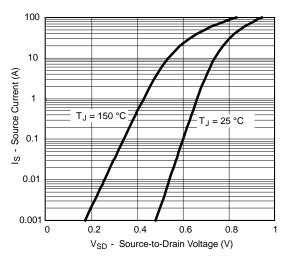




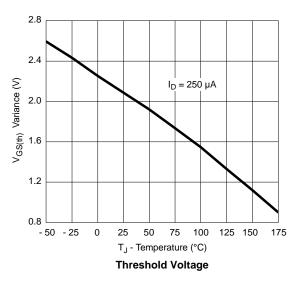
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

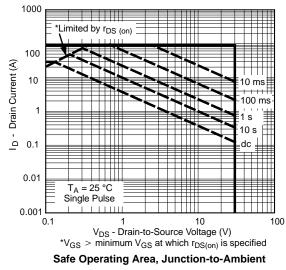




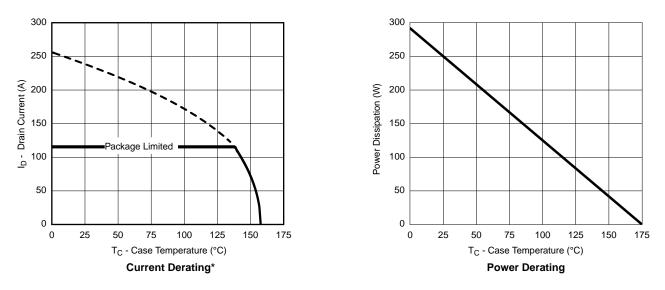


Forward Diode Voltage vs. Temperature



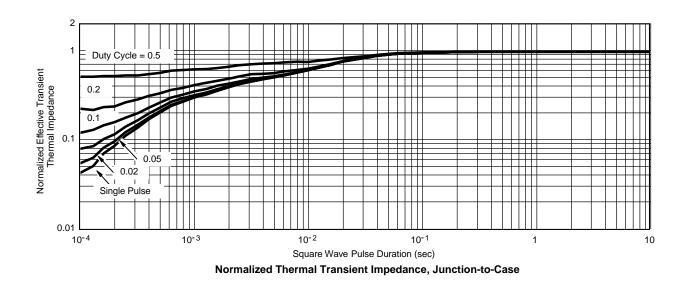






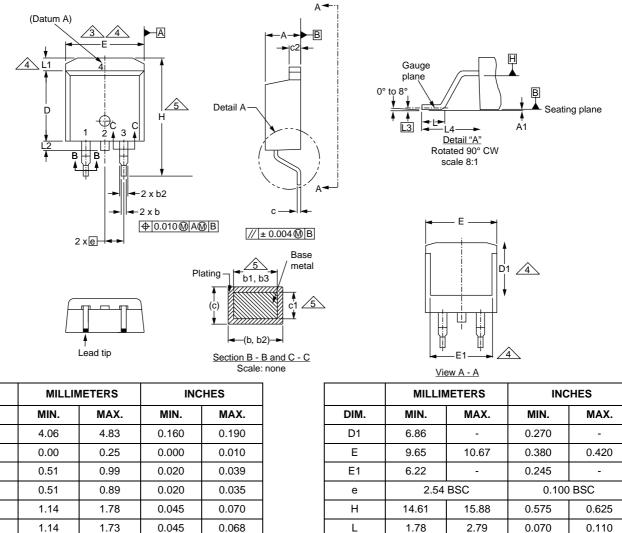
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

*The power dissipation P_D is based on $T_{J(max)} = 175$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





TO-263AB (HIGH VOLTAGE)



D 8.38

DIM.

А

A1

b

b1

b2

b3

с

c1

c2

ECN: S-82110-Rev. A, 15-Sep-08 DWG: 5970

0.38

0.38

1.14

Notes

1. Dimensioning and tolerancing per ASME Y14.5M-1994.

0.74

0.58

1.65

9.65

0.015

0.015

0.045

0.330

0.029

0.023

0.065

0.380

2. Dimensions are shown in millimeters (inches).

3. Dimension D and E do not include mold flash. Mold flash shall not exceed 0.127 mm (0.005") per side. These dimensions are measured at the outmost extremes of the plastic body at datum A.

L1

L2

L3

L4

-

-

4.78

1.65

1.78

5.28

0.25 BSC

- 4. Thermal PAD contour optional within dimension E, L1, D1 and E1.
- 5. Dimension b1 and c1 apply to base metal only.
- 6. Datum A and B to be determined at datum plane H.
- 7. Outline conforms to JEDEC outline to TO-263AB.

0.066

0.070

0.208

-

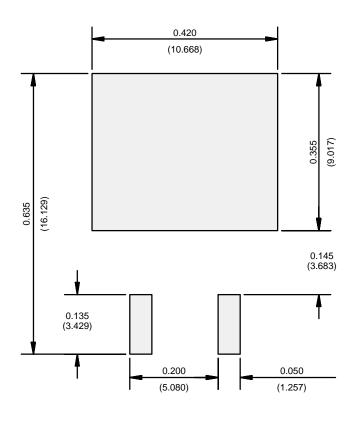
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0.188

0.010 BSC



RECOMMENDED MINIMUM PADS FOR D²PAK: 3-Lead



Recommended Minimum Pads Dimensions in Inches/(mm)



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